	Application/Control No.		Applicant(s)/Patent under Reexamination	tion
Issue Classification			HAIMER, FRANZ	
	Examiner	Art Unit	nit	
	Fulton, Christopher W	2859		
OR	ORIGINAL	INTERNA	INTERNATIONAL CLASSIFICATION	Z
CLASS	SUBCLASS	CLAIMED	NON-CLAIMED	AIMED
33	629	G 0 1 B	5 / 20	
CROSS RE	CROSS REFERENCE(S)			
CLASS SUBCLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
NONE			Total Claims Allowed:	Allowed:
ant Examiner)	(Date)	the little	80	
(Legar Mistruments Examiner) (D	Christopher W. Fulton (Date)	Mu Whaside fell (Date)	O.G. Print Claim(s)	O.G. Print Figure

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